

1200V 30mohm Silicon Carbide Power MOSFET AKCK2M030WAM

Features:

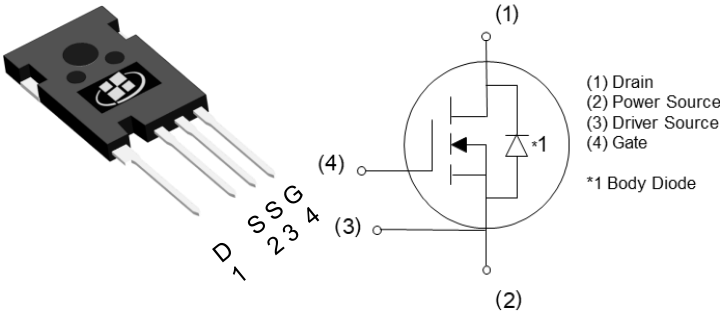
- Low on-resistance
- Fast switching speed with low capacitances
- Fast intrinsic diode with low reverse recovery (Q_{RR})
- Halogen-free, RoHS compliant ^(Note 1)

Applications:

- Motor drives
- DC/DC converters
- Switched mode power supplies
- Solar inverters

Key Performance Parameters:

Parameter	Value	Unit
V_{DS}	1200	V
$R_{DS(on)}$, TYP @ $V_{GS} = 15\text{ V}$	30	m Ω
$R_{DS(on)}$, TYP @ $V_{GS} = 18\text{ V}$	25	m Ω
I_D	76	A
P_D	375	W



Ordering Information:

Ordering Code	Package Type	Marking Code	Form	Packing
AKCK2M030WAM	TO-247-4L	CK2M030WAM	Tube	300 per box

Notes:

1. Contact ALKAIDSEMI sales for detail information

Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Value	Units
V_{DS}	Drain-Source Voltage	1200	V
I_D	Drain Current - Continuous ($T_C = 25^\circ\text{C}$) ^(Note 1)	76	A
	Drain Current - Continuous ($T_C = 100^\circ\text{C}$) ^(Note 1)	54	A
I_{DM}	Drain Current - Pulsed ^(Note 2)	120	A
V_{GS}	Gate-Source Voltage (dynamic)	-8/+22	V
V_{GS}	Gate-Source Voltage (static)	-4/+18	V
P_D	Power Dissipation ($T_C = 25^\circ\text{C}$)	375	W
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +175	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	Value	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Steady-State	0.4	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Steady-State	40	$^\circ\text{C/W}$

Notes:

1. The max drain current limited by maximum junction temperature
2. Repetitive Rating: Pulse width limited by maximum junction temperature

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Static Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 100 μA	1200			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 1200 V, V _{GS} = 0 V		5	50	μA
I _{GSS}	Gate Leakage Current	V _{GS} = 18 V, V _{DS} = 0 V			100	nA
		V _{GS} = - 4 V, V _{DS} = 0 V			100	nA
V _{GS(TH)}	Gate Threshold voltage	V _{DS} = V _{GS} , I _D = 11.5 mA	2	2.6	4	V
		V _{DS} = V _{GS} , I _D = 11.5 mA, T _J = 175 °C		1.8		V
R _{DS(ON)}	Drain-Source on-state resistance	V _{GS} = 15 V, I _D = 40 A		30	40	mΩ
		V _{GS} = 15 V, I _D = 40 A, T _J = 175 °C		48		mΩ
		V _{GS} = 18 V, I _D = 40 A		25	34	mΩ
		V _{GS} = 18 V, I _D = 40 A, T _J = 175 °C		45		mΩ
G _{FS}	Forward Transconductance	V _{DS} = 20 V, I _D = 40 A		27		S
		V _{DS} = 20 V, I _D = 40 A, T _J = 175 °C		28		S
Dynamic Characteristics						
C _{ISS}	Input Capacitance	V _{DS} = 800 V, V _{GS} = 0 V, F = 100 kHz, V _{AC} = 25 mV		3545		pF
C _{OSS}	Output Capacitance			145		pF
C _{RSS}	Reverse Transfer Capacitance			13		pF
E _{OSS}	C _{OSS} Stored Energy			58		μJ
R _G	Gate Resistance	F = 1 MHz, V _{AC} = 25 mV		1		Ω
Q _{GS}	Gate-Source Charge	V _{DS} = 800 V , I _D = 40 A, V _{GS} = -4/+15 V		39		nC
Q _{GD}	Gate-Drain Charge			55		nC
Q _G	Total Gate Charge			155		nC

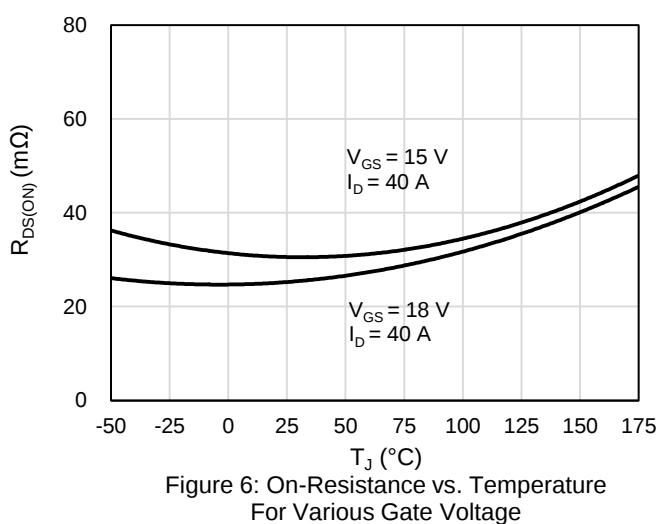
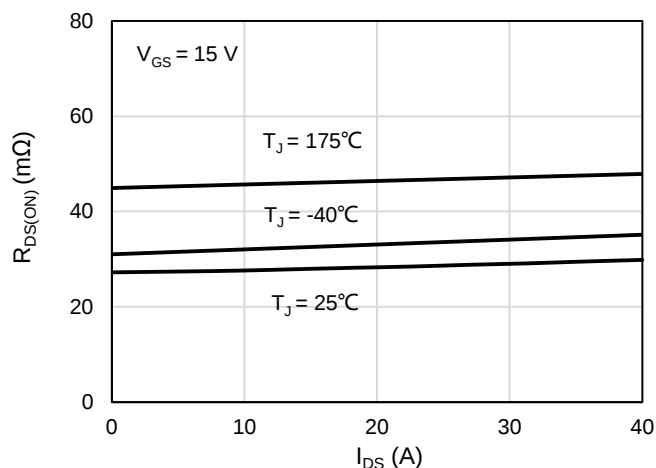
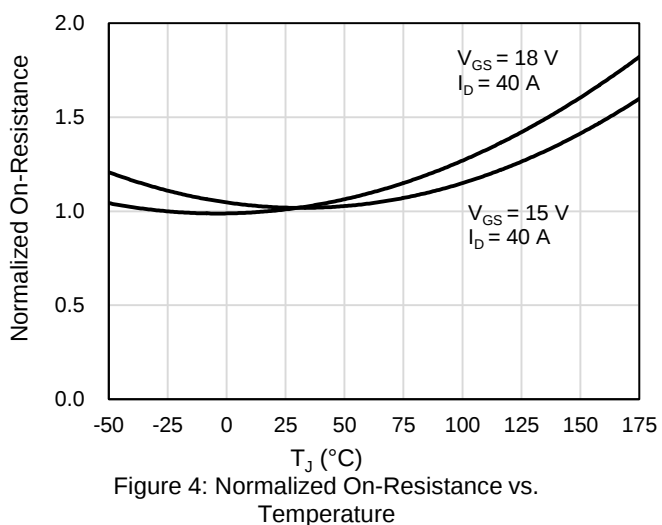
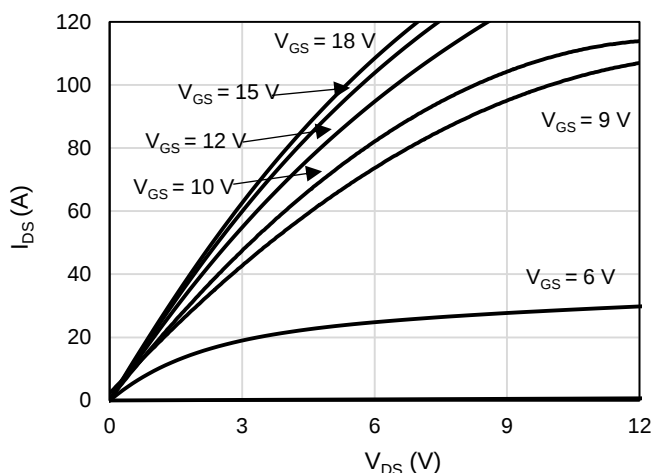
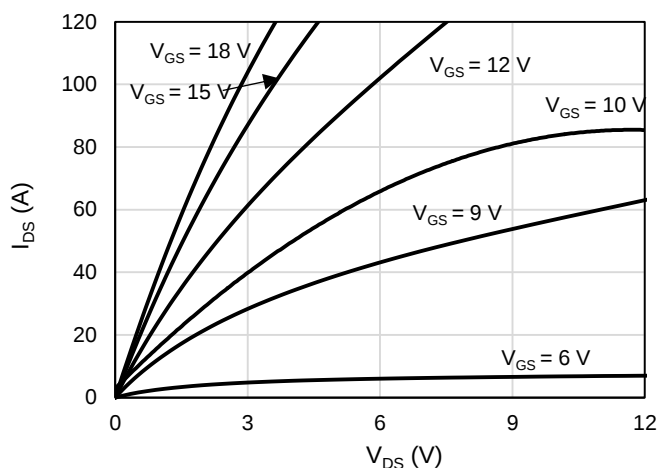
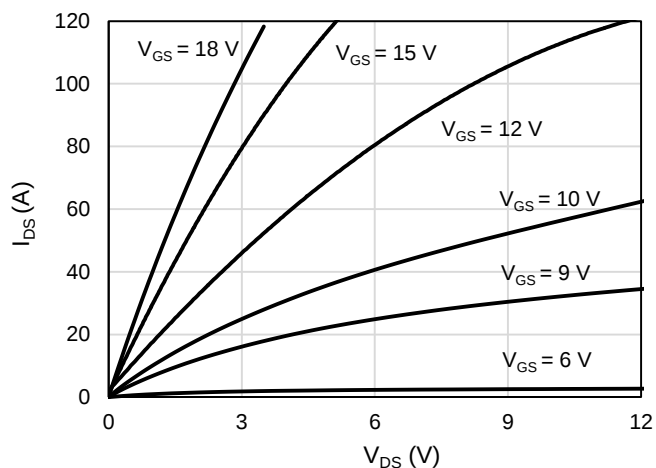
Switching Characteristics

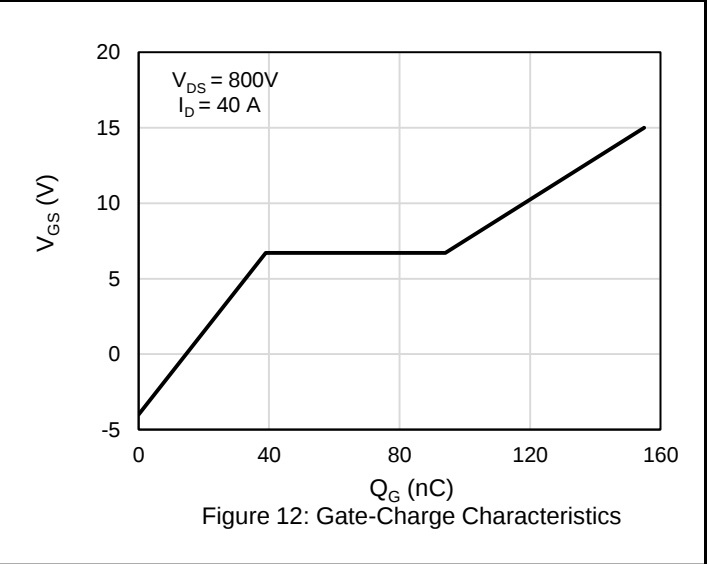
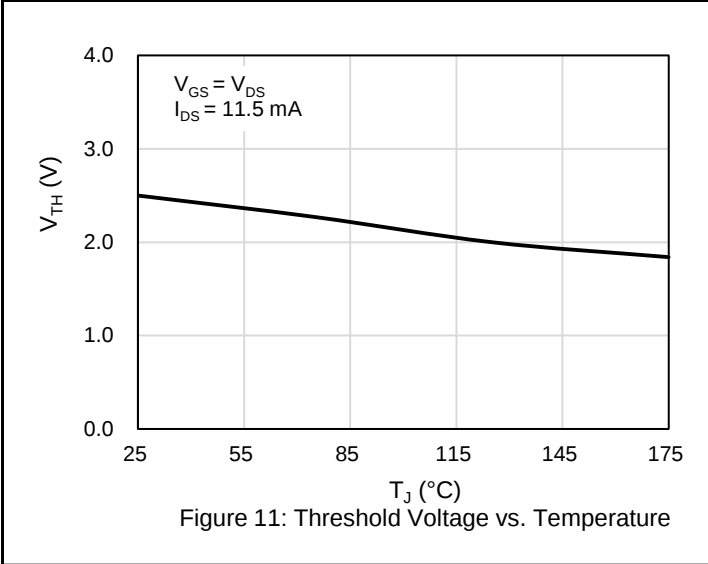
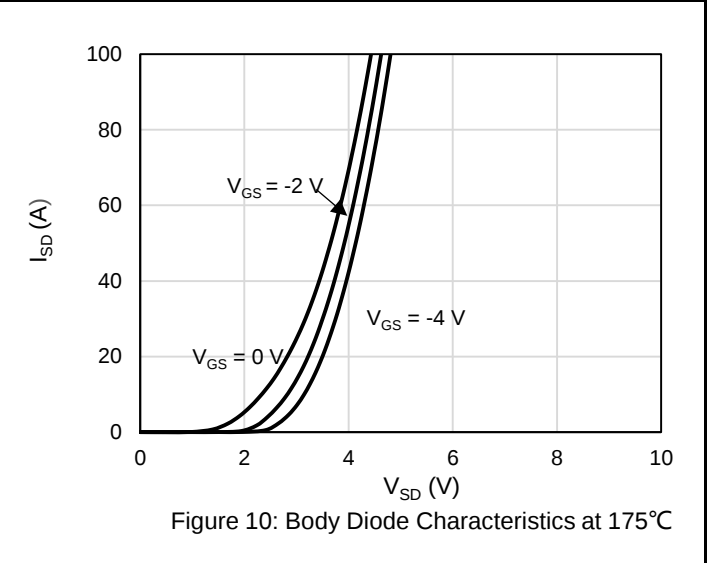
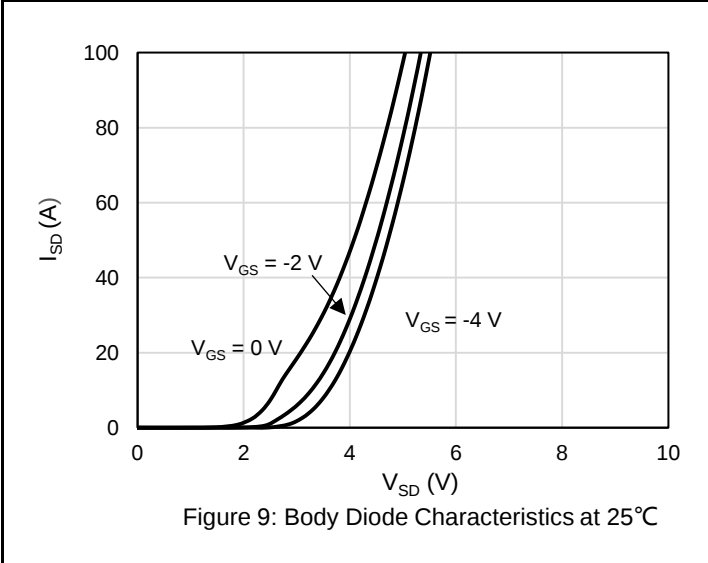
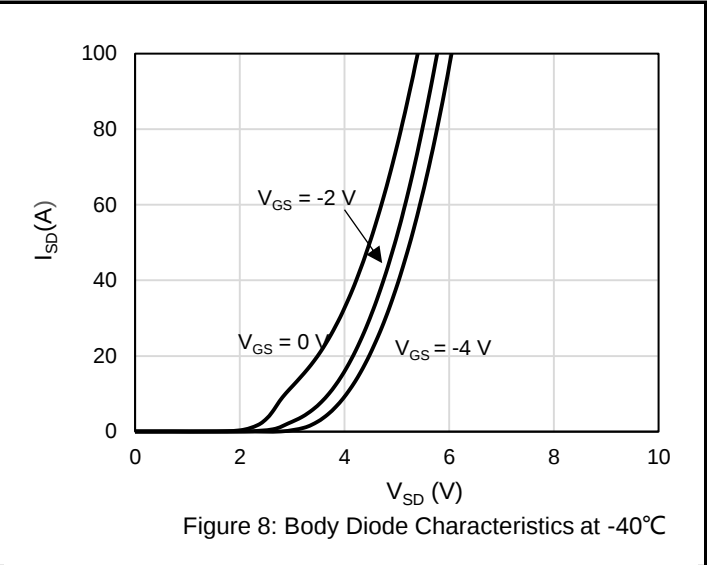
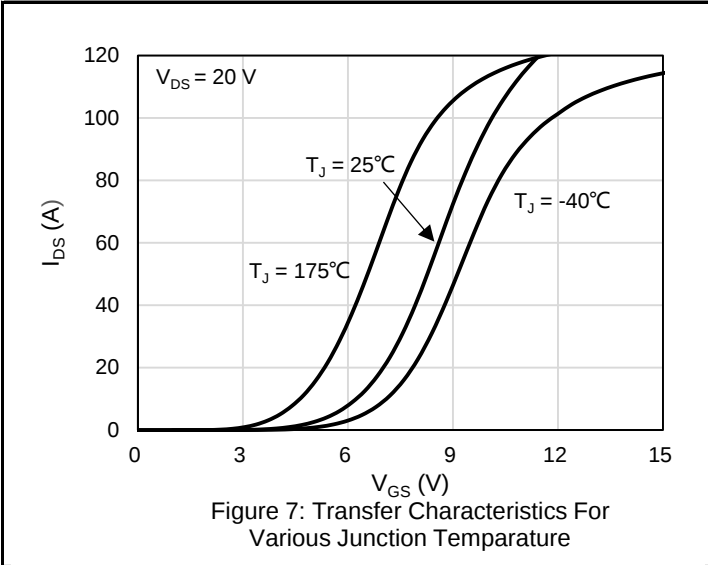
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
$T_{D(ON)}$	Turn On Delay Time	$V_{DD} = 800\text{ V}$, $I_D = 40\text{ A}$, $V_{GS} = -4/+15\text{ V}$, $R_{G,EXT} = 2.5\ \Omega$ $L = 40\text{ nH}$ Diode: Body Diode at $V_{GS} = -4\text{V}$		14		ns
T_R	Rise Time			12		ns
$T_{D(OFF)}$	Turn Off Delay Time			45		ns
T_F	Fall Time			18		ns
E_{ON}	Turn On Energy			917		μJ
E_{OFF}	Turn Off Energy			142		μJ
$T_{D(ON)}$	Turn On Delay Time	$V_{DD} = 800\text{ V}$, $I_D = 40\text{ A}$, $V_{GS} = -4/+15\text{ V}$, $R_{G,EXT} = 2.5\ \Omega$ $L = 40\text{ nH}$ Diode: Body Diode at $V_{GS} = -4\text{V}$ $T_J = 175\text{ }^\circ\text{C}$		10		ns
T_R	Rise Time			11		ns
$T_{D(OFF)}$	Turn Off Delay Time			52		ns
T_F	Fall Time			20		ns
E_{ON}	Turn On Energy			1066		μJ
E_{OFF}	Turn Off Energy			178		μJ

Drain-Source Diode Characteristics ($T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted)

I_S	Maximum Continuous Drain-Source Diode Forward Current			76	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current			120	A
V_{SD}	Diode Forward Voltage	$V_{GS} = -4\text{ V}$, $I_{SD} = 20\text{ A}$		4	V
		$V_{GS} = -4\text{ V}$, $I_{SD} = 20\text{ A}$, $T_J = 175\text{ }^\circ\text{C}$		3.5	V
I_{RM}	Peak Reverse Recovery Current	$V_{GS} = -4\text{ V}$, $I_{SD} = 40\text{ A}$, $V_R = 800\text{ V}$, $di/dt = 1150\text{ A}/\mu\text{S}$		15	A
T_{RR}	Reverse Recovery Time			25	ns
Q_{RR}	Reverse Recovery Charge			172	nC
I_{RM}	Peak Reverse Recovery Current	$V_{GS} = -4\text{ V}$, $I_{SD} = 40\text{ A}$, $V_R = 800\text{ V}$, $di/dt = 1150\text{ A}/\mu\text{S}$ $T_J = 175\text{ }^\circ\text{C}$		21	A
T_{RR}	Reverse Recovery Time			41	ns
Q_{RR}	Reverse Recovery Charge			395	nC

Electrical Characteristics Diagrams





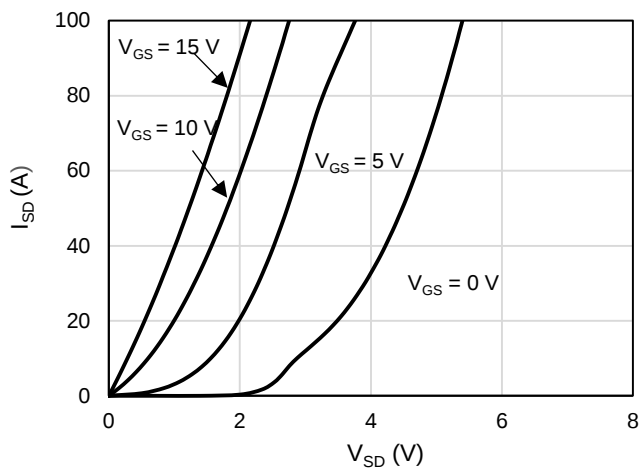


Figure 13: 3rd Quadrant Characteristics at -40°C

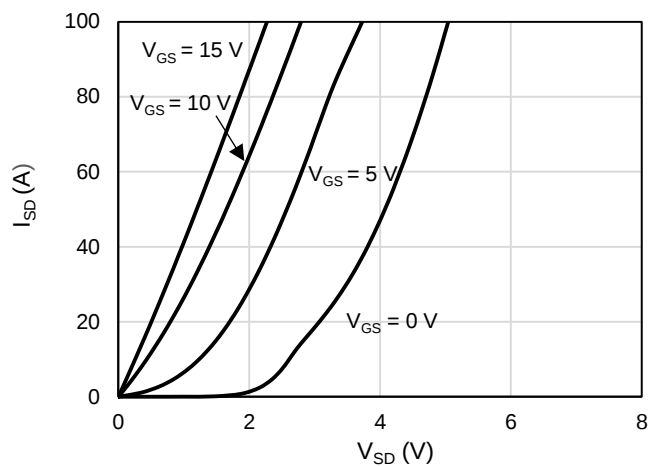


Figure 14: 3rd Quadrant Characteristics at 25°C

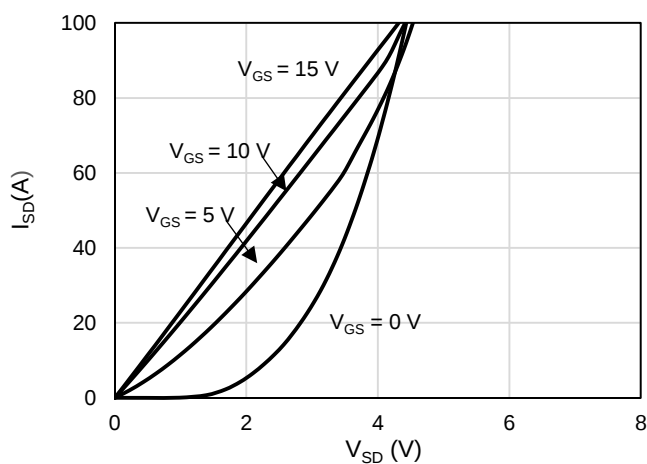


Figure 15: 3rd Quadrant Characteristics at 175°C

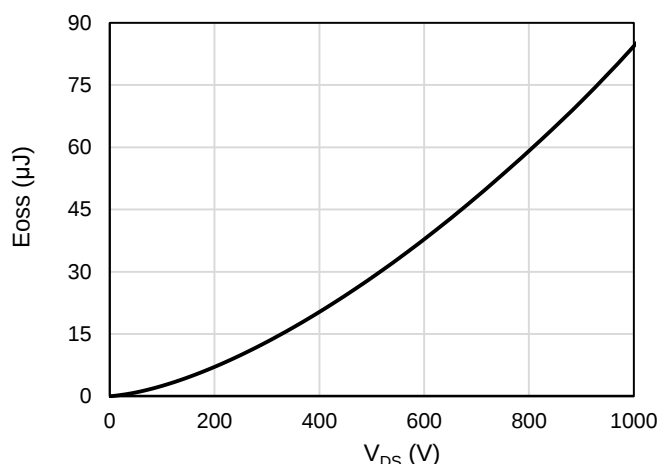


Figure 16: Output Capacitor Stord Energy

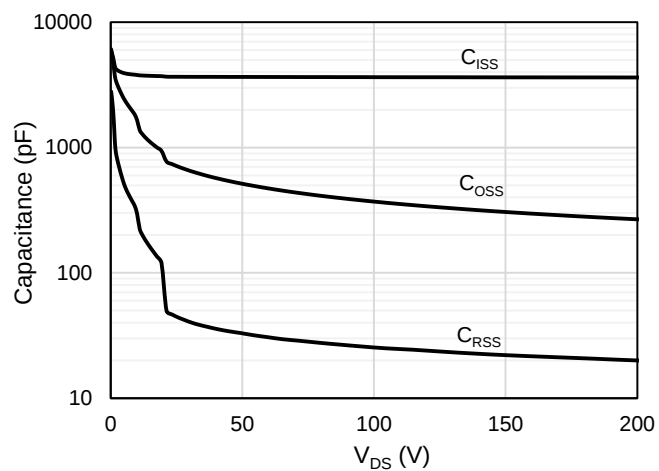


Figure 17: Capacitance Characteristics (0 - 200V)

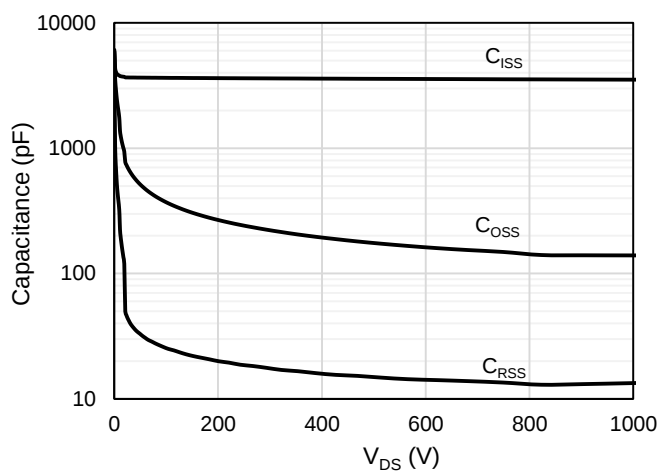


Figure 18: Capacitance Characteristics (0-1000V)

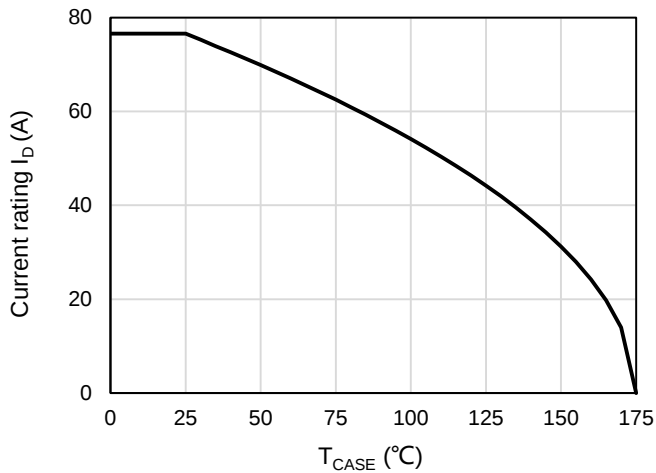


Figure 19: Current De-rating

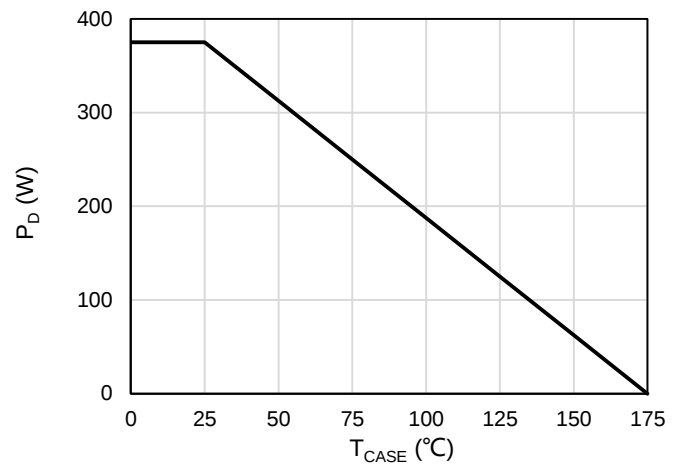


Figure 20: Maximum Power Dissipation Derating vs Case Temperature

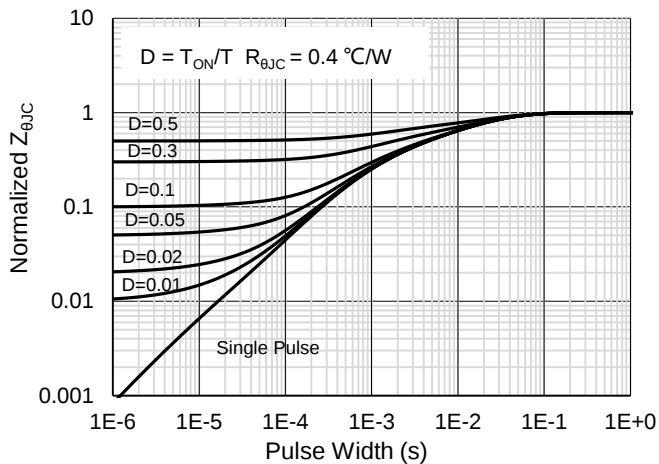


Figure 21: Normalized Maximum Transient Thermal Impedance

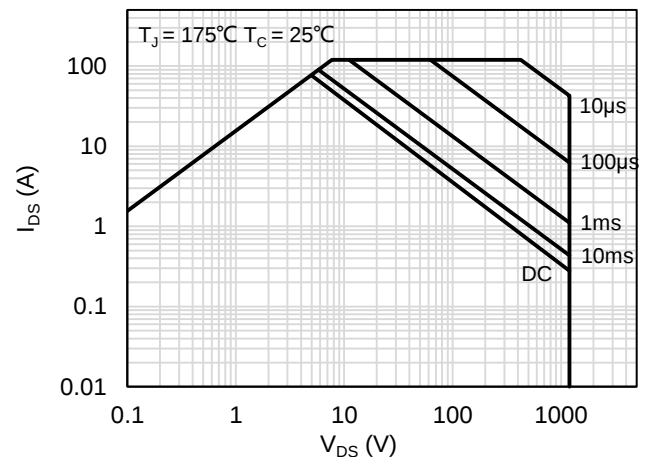
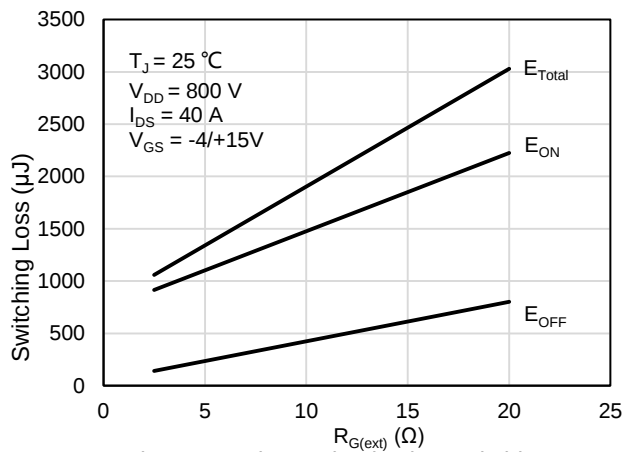
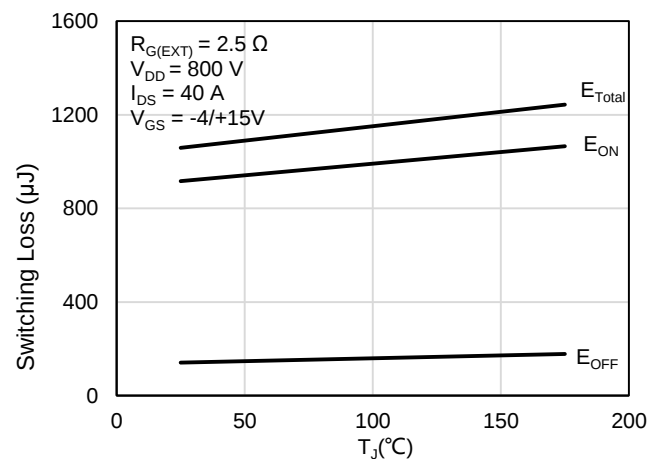


Figure 22: Maximum Forward Biased Safe Operating Area

Figure 23: Clamped Inductive Switching Energy vs. $R_{G(ext)}$ Figure 24: Clamped Inductive Switching Energy vs. T_J

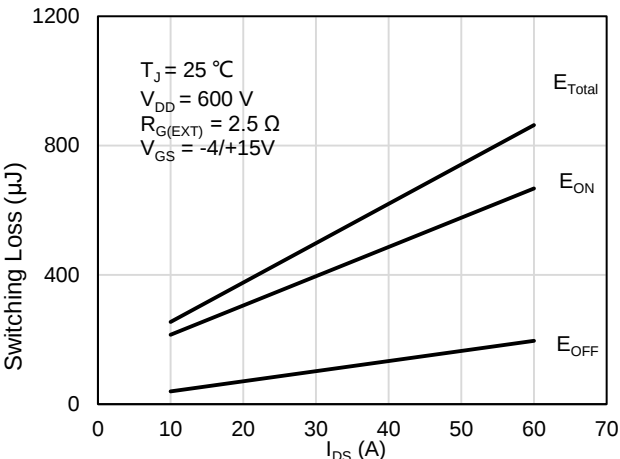


Figure 25: Clamped Inductive Switching Energy vs. Drain Current ($V_{DD} = 600\text{ V}$)

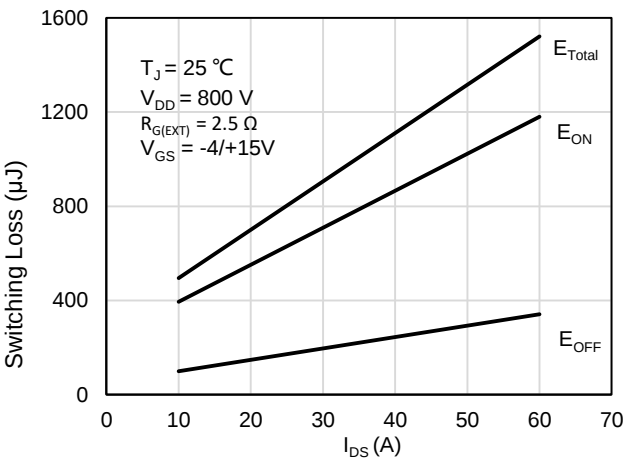


Figure 26: Clamped Inductive Switching Energy vs. Drain Current ($V_{DD} = 800\text{ V}$)

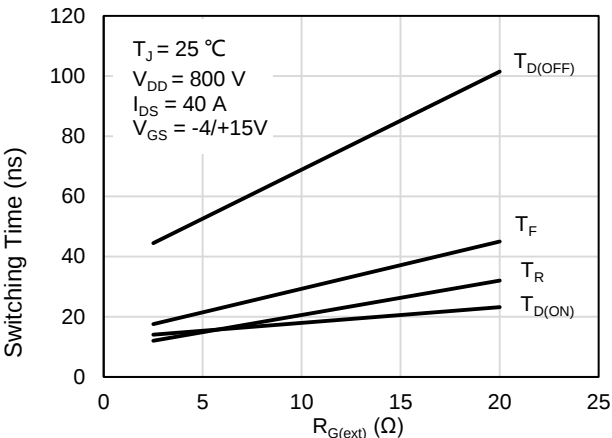
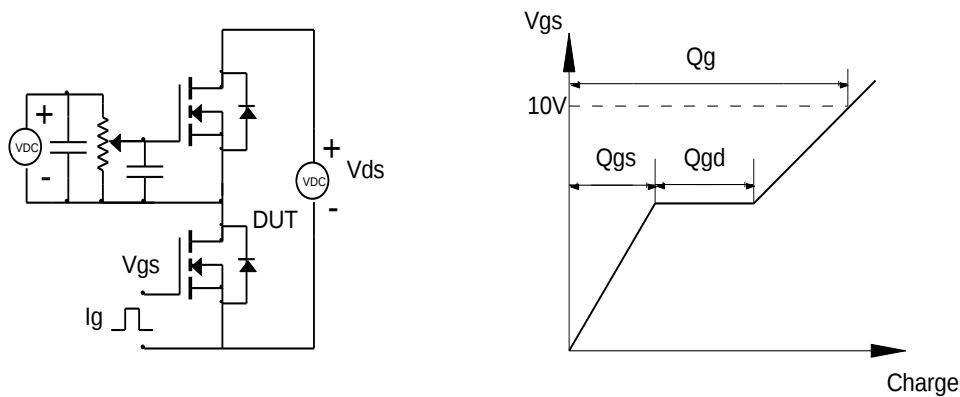


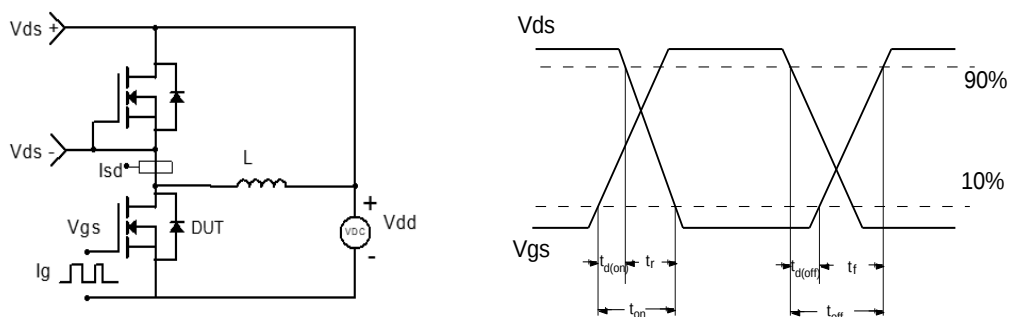
Figure 27: Clamped Inductive Switching Time vs. $R_{G(EXT)}$

Test Circuit and Waveform

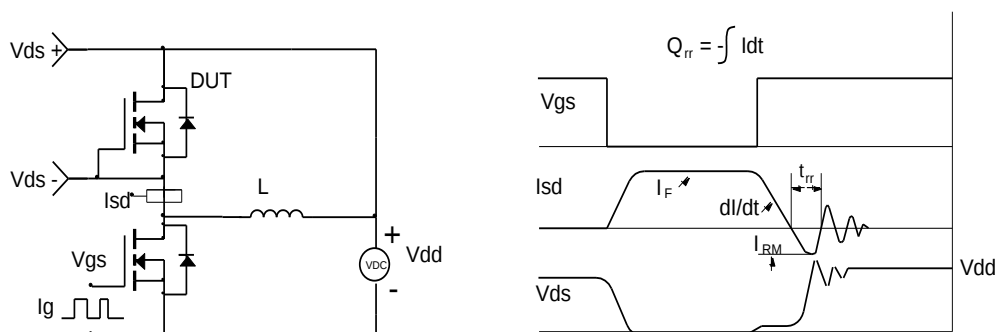
Gate Charge Test Circuit & Waveform



Clamped Inductive Switching Test Circuit & Waveforms

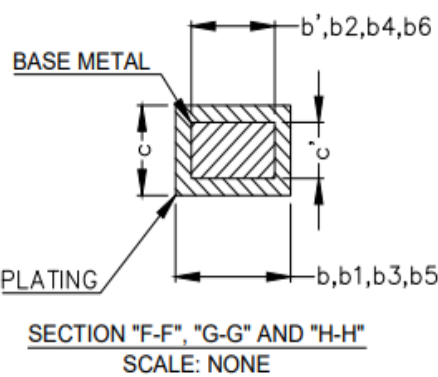
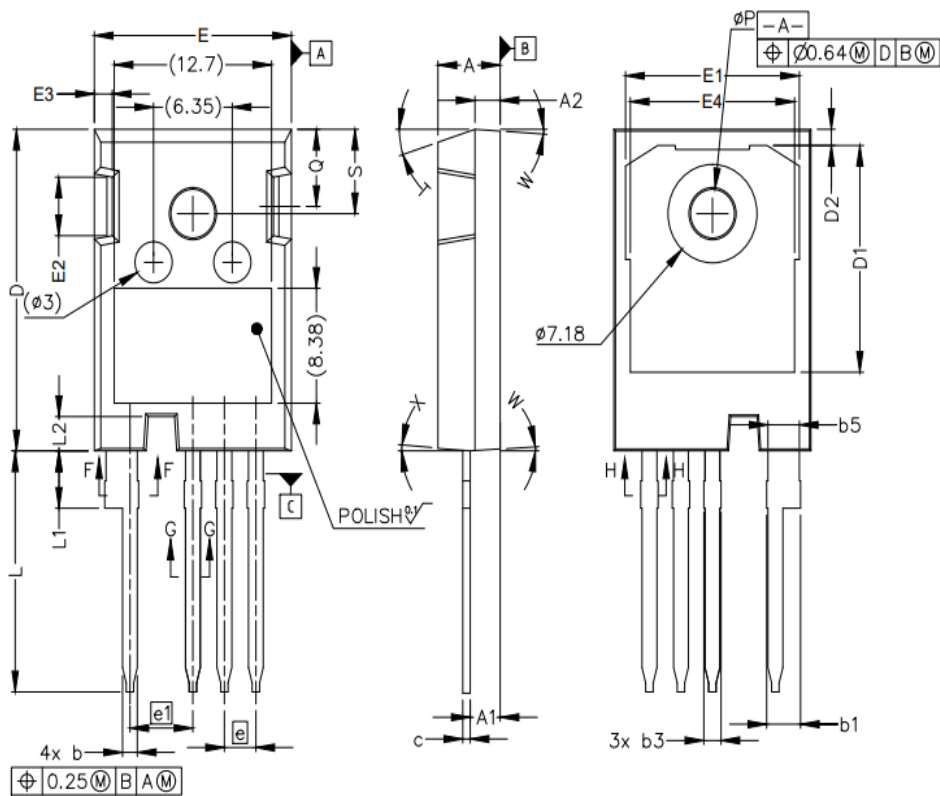


Diode Recovery Test Circuit & Waveforms



Package Outlines

TO-247-4L PKG Outlines



SYMBOL	MILLIMETERS	
	MIN	MAX
A	4.83	5.21
A1	2.29	2.54
A2	1.91	2.16
b'	1.07	1.28
b	1.07	1.33
b1	2.39	2.94
b2	2.39	2.84
b3	1.07	1.60
b4	1.07	1.50
b5	2.39	2.69
b6	2.39	2.64
c'	0.55	0.65
c	0.55	0.68
D	23.30	23.60
D1	16.25	17.65
D2	0.95	1.25
E	15.75	16.13
E1	13.10	14.15
E2	3.68	5.10
E3	1.00	1.90
E4	12.38	13.43
e	2.54 BSC	
e1	5.08 BSC	
N	4	
L	17.31	17.82
L1	3.97	4.37
L2	2.35	2.65
ϕP	3.51	3.65
Q	5.49	6.00
S	6.04	6.30
T	17.5° REF.	
W	3.5° REF.	
X	4° REF.	

Marking Information



Note:

CK2M030WAM = Product Name Code

XXXXXXX = Date Code

Contact ALKAIDSEMI sales for detail information

Revision History

Revision	Release Date	Remark
Rev.1.1	2023/6/12	

Disclaimer

The information given in this document describes the independent performance of the product, but similar performance is not guaranteed under other working conditions, and cannot be guaranteed when installed with other products or equipment. To achieve the required performance of the product in actual scenarios, the customer should conduct a complete application test to assess the functionality of the product.

Alkaidsemi assumes no responsibility for equipment failures result from using products at values that exceed the ratings, operating conditions, or other parameters listed in the product specifications.

The product described in this specification is not applicable for aerospace or other applications which requires high reliability. Customers using or selling these products for use in medical, life-saving, or life-sustaining applications do so at their own risk and agree to fully indemnify.

Due to product or technical improvements, the information described or contained herein may be changed without prior notice.